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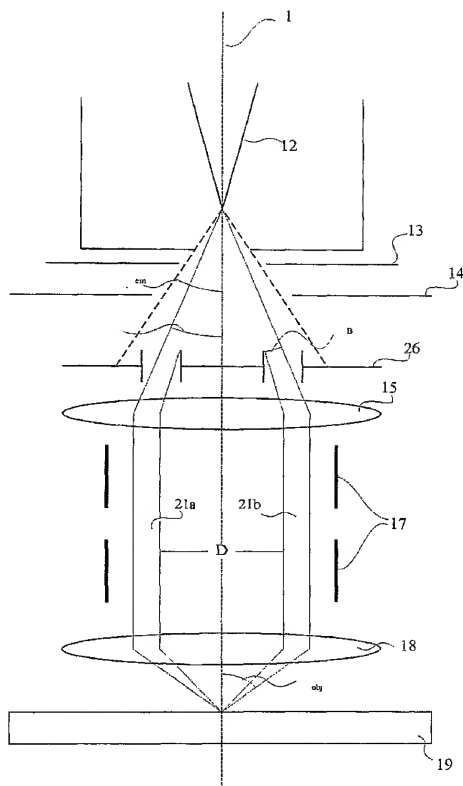
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[Continued on next page]

(54) Title: HIGH CURRENT DENSITY PARTICLE BEAM SYSTEM

(57) Abstract: The present invention relates to charged particle beam devices. The devices comprise an emitter (12) for emitting charged particles; an aperture arrangement (26; 86) with at least two apertures (36) for separating the emitted charged particles into at least two independent charged particle beams; and an objective lens (18) for focusing the at least two independent charged particle beams, whereby the independent charged particle beams are focused onto the same location within the focal plane.





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